



Click [here](#) for the 3D model.

#### General Information

|                |                        |
|----------------|------------------------|
| Series         | LDE                    |
| Dielectric     | Metallized PEN Stacked |
| Style          | SMD Chip               |
| Features       | Automotive Grade       |
| RoHS           | Yes                    |
| Qualifications | AEC-Q200               |
| AEC-Q200       | Yes                    |
| Shelf Life     | 104 Weeks              |
| MSL            | 3                      |

#### Dimensions

|           |                   |
|-----------|-------------------|
| Chip Size | 1812              |
| L         | 4.7mm +0.3/-0.2mm |
| W         | 3.3mm +/-0.3mm    |
| T         | 1.7mm MAX         |
| B         | 0.4mm +0.5/-0.3mm |

#### Packaging Specifications

|                    |      |
|--------------------|------|
| Packaging          | T&R  |
| Packaging Quantity | 4000 |

#### Specifications

|                       |            |
|-----------------------|------------|
| Capacitance           | 3,300 pF   |
| Tolerance             | 10%        |
| Voltage DC            | 50 VDC     |
| Voltage AC            | 40 VAC     |
| Temperature Range     | -55/+125°C |
| Rated Temperature     | 125°C      |
| Dissipation Factor    | 0.8% 1kHz  |
| Insulation Resistance | 1 GOhms    |
| Max dV/dt             | 100 V/us   |

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